



Demonstration of JEOL JEM-ARM200F Cs-corrected TEM

By JEOL (Japan) Engineer

Date: 21 – 22 September 2017 (Thursday & Friday)

Time: 10:00 am – 17:00 pm

Venue: Room 2212 (near lift 22), Academic Building, HKUST

The engineer will demonstrate the operation of the newly installed JEOL JEM-ARM200F Cs-corrected TEM in MCPF, HKUST.

The demonstration will include:

1. High resolution STEM-HAADF Imaging at 200KV, 80 KV, 60KV & 30KV;
2. Spectrum analysis and mapping with both Energy Dispersive X-ray Spectrometer (EDS) and Electron Energy Loss Spectrometer (EELS);
3. Annular Bright Field (ABF) observation of light elements.

Admission: In view of limited space, this demonstration is open to very experienced TEM users only. Please contact Dr. CAI Yuan (caiyuan@ust.hk) to register your attendance **not later than 11 September 2017 (Monday)**. A confirmation letter will be sent to the participants on 12 September 2017 (Tuesday).

About JEOL JEM-ARM200F Cs-corrected TEM in MCPF, HKUST

JEOL JEM-ARM200F Cs-corrected TEM is housed in a purpose-built room that limits environmental variations (vibration, thermal, moisture and electromagnetic interference) in MCPF, HKUST. This atomic resolution analytical microscope is integrated with a Cs-corrector in the condenser lens system and a cold field emission gun. It achieves an ultimate STEM-HAADF resolution of 83 pm at 200kV. Atom-to-atom chemical mapping of materials, including energy-dispersive X-ray spectroscopy (EDS) and electron energy-loss spectroscopy (EELS), is also possible. Tomography and 3D Reconstruction is available under both TEM and STEM modes.

For enquiries, please contact Dr. CAI Yuan (Tel: 2358 8723, caiyuan@ust.hk).